

In the specification, please amend paragraph [0012] as follows:

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A' [0012] In a preferred aspect of the present invention, the image measurement unit may be configured to measure the characteristic of the specimen image by directly measuring light emitted from the specimen and not refracted by the main optical system, as is illustrated in FIG. 4. Alternatively, the image measurement unit may be configured to measure the characteristic of the specimen image by measuring light emitted from the specimen and refracted by the main optical system into the main beam path. The device may further comprise a beam splitter configured to reflect a portion of the specimen image from the main beam path to the image measurement unit.

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In the specification, please add the following new paragraph after the current paragraph [0023]:

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A2 [0023A] FIG. 4 is a schematic drawing of another preferred embodiment of the present invention.

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